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**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Reliability test method for optoelectronic devices used in
telecommunications**

通信用光电子器件可靠性试验方法
(English Translation)

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What this standard covers

This standard specifies the general requirements for optoelectronic devices for communication reliability test methods and detailed requirements, including: test purposes, equipment, procedures, , inspection and failure criteria conditions. This standard applies to communications optoelectronic devices, including but not limited to the laser diode, emitting diodes, photodiode, avalanche photodiode and the composition of their components or modules, referred to as " optoelectronic devices. " Other areas may also refer to the use of optoelectronic devices.

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